## FORM PTO-1449

Atty Docket Serial No. 25818 10/702,044 Applicant

FINE, et al.

Filing Date

Group Art Unit

Initial					Nov. 6, 200	3	Not yet	assigned	
Initial	U.S. PATENT DOCUMENTS								
### 3,346,002 1994 Caro 1992  ### 1992  ### 1993  ### 1994  ### 1998  ### 1998  ### 1999  ### Ab 5,792,668 Aug. 11, 1998  ### 1999  ### Ab 5,792,668 Aug. 24, 1999  ### Chou Nov. 25	II				Name	Class		Filing Date	
### AB	m	AA	5,348,002		Caro			Apr. 23, 1992	
AD   6,049,728   Apr. 11, 2000   Chou   Nov, 12 1998	ax	AB	5,792,668		Fuller et al.			Apr. 15, 1996	
AE 6,049,728 2000 Chou 1998  AE 6,400,972 June 4, 2002 Fine Dec. 21 1999  MAF 6,466,806 Oct. 15, 2002 May 17, 2000  AG 2002/0155615 Oct. 24, 2002 Novikov et al. Feb. 5, 2002  FOREIGN PATENT DOCUMENTS  Document Number Date Country Class Sub-Class Jation  AH WO 01/96872 Dec. 20, 2001  AI WO 01/45553 June 28, 2001  AJ WO 02/069791 Sep. 12, 2002  MIPO N/A  AJ WO 02/069791 Sep. 12, 2002  MIPO N/A  AK 0 282 234 Sep. 14, 1988  AL WO 00/43759 July 27, 2000  May 17, 20	M	AC	5,941,821		Chou			Nov. 25, 1997	
AF 6,466,806 Oct. 15, 2002 Geva et al. May 17, 2000  M AG 2002/0155615 Oct. 24, 2002 Novikov et al. Feb. 5, 2002  FOREIGN PATENT DOCUMENTS  Document Number Date Country Class Sub- Class Jation  AH WO 01/96872 Dec. 20, WIPO N/A  AI WO 01/45553 June 28, 2001  AJ WO 02/069791 Sep. 12, 2002  MIPO N/A  AX 0 282 234 Sep. 14, 1988  AX WO 00/43759 July 27, 2000  May 17, 2000  Feb. 5, 2002  Foreign Patent Documents  Class Sub- Class Jation  N/A  N/A  N/A  N/A  N/A	m	AD	6,049,728		Chou	$\perp$		Nov, 12, 1998	
## 6,466,806 2002 GeVa et al. 2000  ### 6,466,806 2002 GeVa et al. 2000  ### 6,466,806 2002 GeVa et al. 2000  ### Feb. 5, 2002  ### FOREIGN PATENT DOCUMENTS    Document Number   Date   Country   Class Sub-Class lation	MK	AE	6,400,972		Fine			Dec. 21, 1999	
### FOREIGN PATENT DOCUMENTS    Document Number	M.	AF	6,466,806	•	Geva et al.			May 17, 2000	
Document Number   Date   Country   Class   Sub-Class   Jation	M	AG	2002/0155615		Novikov et al.			Feb. 5, 2002	
Number         Date         Country         Class Class lation           AH         WO 01/96872         Dec. 20, 2001         WIPO         N/A           AI         WO 01/45553         June 28, 2001         WIPO         N/A           AJ         WO 02/069791         Sep. 12, 2002         WIPO         N/A           AK         0 282 234         Sep. 14, 1988         EP         N/A           AL         WO 00/43759         July 27, 2000         WIPO         N/A	FOREIGN PATENT DOCUMENTS								
AH 2001  AI WO 01/45553 June 28, 2001  AJ WO 02/069791 Sep. 12, 2002  AK 0 282 234 Sep. 14, 1988  AK WO 00/43759 July 27, 2000  MIPO  N/A  N/A  N/A				Date	Country	Class	, i	Trans- Jation	
M AI 2001  AJ WO 02/069791 Sep. 12, WIPO N/A  M AK 0 282 234 Sep. 14, EP N/A  1988 WO 00/43759 July 27, 2000 N/A	juj	АН	WO 01/96872		WIPO			N/A	
M AJ 2002  M AK 0 282 234 Sep. 14, EP N/A  1988 WO 00/43759 July 27, WIPO N/A	M	AI	WO 01/45553		WIPO			N/A	
M AL WO 00/43759 July 27, 2000 WIPO N/A	Mx	AJ	WO 02/069791		WIPO		<u>,</u>	N/A	
2000 / AL   2000   /	Mx	AK	0 282 234		EP			n/a	
OTHER (Including Author Title Date Pertinent Dages etc.)	M-	AL	WO 00/43759		WIPO			N/A	
orman (including Author, little, Date, Feltiment rages, etc.)									
Feldman, Yuri, et al., "Time domain dielectric spectroscopy: Ar advanced measuring system". Rev. Sci. Instrum., vol. 67, no. 5 pp. 3208-3216, September 1996.									

Examiner

Date Considered

Initial if reference considered, whether or not citation is in conformance with MPEP \$ Draw line through citation if not in conformance and not considered.

Include copy of this form with next communication to Applicant. EXAMINER: